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### Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Active
Number of LABs/CLBs	600
Number of Logic Elements/Cells	2700
Total RAM Bits	40960
Number of I/O	92
Number of Gates	100000
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/xilinx/xc2s100-5tq144i">https://www.e-xfl.com/product-detail/xilinx/xc2s100-5tq144i</a>

## General Overview

The Spartan-II family of FPGAs have a regular, flexible, programmable architecture of Configurable Logic Blocks (CLBs), surrounded by a perimeter of programmable Input/Output Blocks (IOBs). There are four Delay-Locked Loops (DLLs), one at each corner of the die. Two columns of block RAM lie on opposite sides of the die, between the CLBs and the IOB columns. These functional elements are interconnected by a powerful hierarchy of versatile routing channels (see Figure 1).

Spartan-II FPGAs are customized by loading configuration data into internal static memory cells. Unlimited reprogramming cycles are possible with this approach. Stored values in these cells determine logic functions and interconnections implemented in the FPGA. Configuration data can be read from an external serial PROM (master

serial mode), or written into the FPGA in slave serial, slave parallel, or Boundary Scan modes.

Spartan-II FPGAs are typically used in high-volume applications where the versatility of a fast programmable solution adds benefits. Spartan-II FPGAs are ideal for shortening product development cycles while offering a cost-effective solution for high volume production.

Spartan-II FPGAs achieve high-performance, low-cost operation through advanced architecture and semiconductor technology. Spartan-II devices provide system clock rates up to 200 MHz. In addition to the conventional benefits of high-volume programmable logic solutions, Spartan-II FPGAs also offer on-chip synchronous single-port and dual-port RAM (block and distributed form), DLL clock drivers, programmable set and reset on all flip-flops, fast carry logic, and many other features.

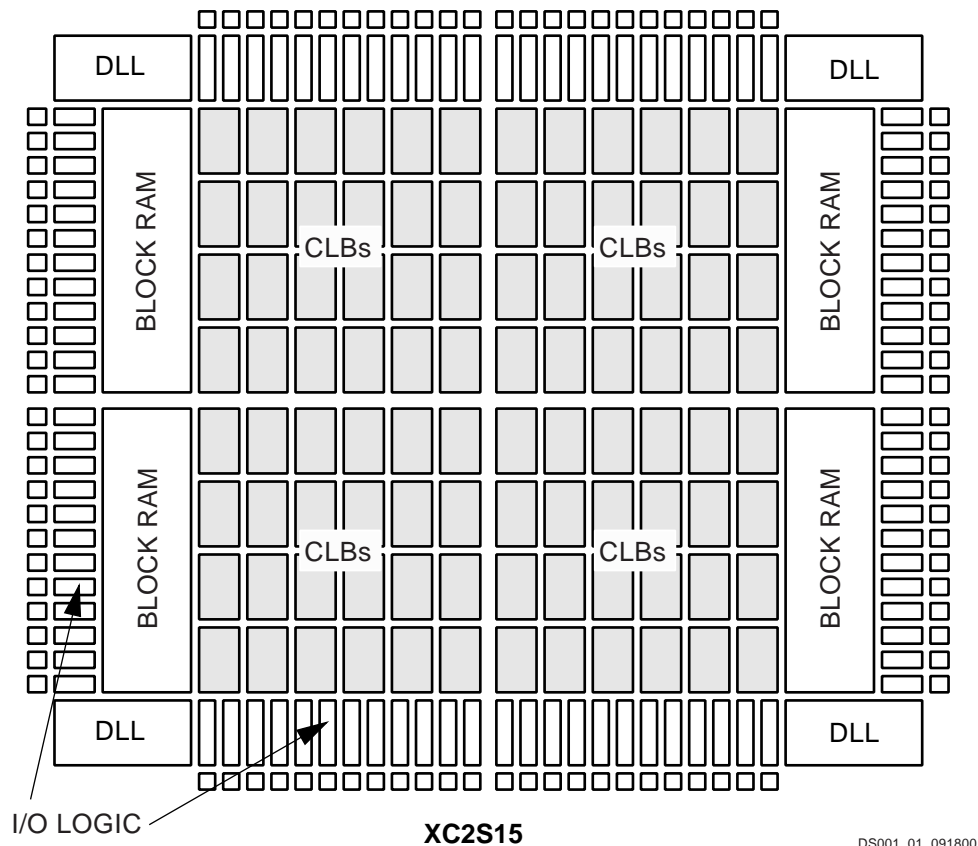


Figure 1: Basic Spartan-II Family FPGA Block Diagram

## Spartan-II Product Availability

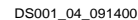
Table 2 shows the maximum user I/Os available on the device and the number of user I/Os available for each device/package combination. The four global clock pins are usable as additional user I/Os when not used as a global clock pin. These pins are not included in user I/O counts.

Table 2: Spartan-II FPGA User I/O Chart<sup>(1)</sup>

Device	Maximum User I/O	Available User I/O According to Package Type					
		VQ100 VQG100	TQ144 TQG144	CS144 CSG144	PQ208 PQG208	FG256 FGG256	FG456 FGG456
XC2S15	86	60	86	(Note 2)	-	-	-
XC2S30	92	60	92	92	(Note 2)	-	-
XC2S50	176	-	92	-	140	176	-
XC2S100	176	-	92	-	140	176	(Note 2)
XC2S150	260	-	-	-	140	176	260
XC2S200	284	-	-	-	140	176	284

**Notes:**

1. All user I/O counts do not include the four global clock/user input pins.
2. Discontinued by [PDN2004-01](#).



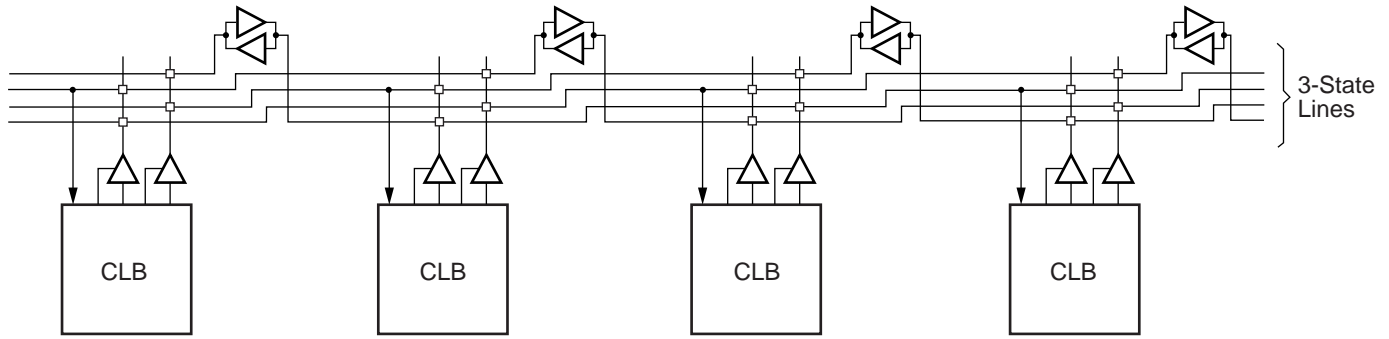
**Figure 4: Spartan-II CLB Slice** (two identical slices in each CLB)

Storage elements in the Spartan-II FPGA slice can be configured either as edge-triggered D-type flip-flops or as level-sensitive latches. The D inputs can be driven either by function generators within the slice or directly from slice inputs, bypassing the function generators.

opposite state. Alternatively, these signals may be configured to operate asynchronously.

### ***Additional Logic***

The F5 multiplexer in each slice combines the function generator outputs. This combination provides either a function generator that can implement any 5-input function, a 4:1 multiplexer, or selected functions of up to nine inputs.



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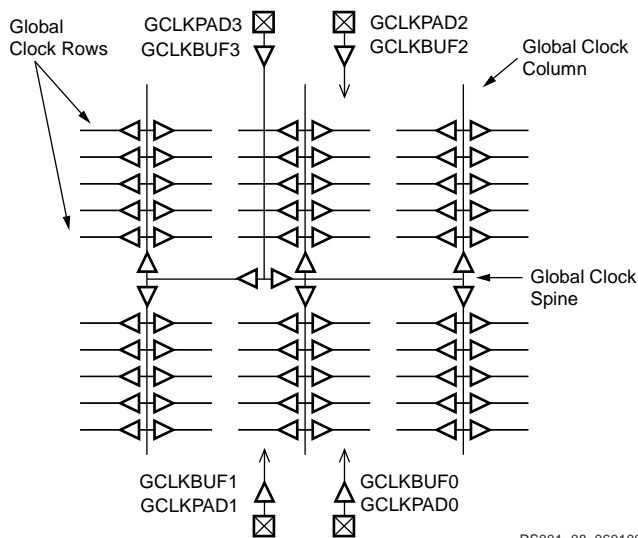
Figure 7: BUFT Connections to Dedicated Horizontal Bus Lines

## Clock Distribution

The Spartan-II family provides high-speed, low-skew clock distribution through the primary global routing resources described above. A typical clock distribution net is shown in Figure 8.

Four global buffers are provided, two at the top center of the device and two at the bottom center. These drive the four primary global nets that in turn drive any clock pin.

Four dedicated clock pads are provided, one adjacent to each of the global buffers. The input to the global buffer is selected either from these pads or from signals in the general purpose routing. Global clock pins do not have the option for internal, weak pull-up resistors.



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Figure 8: Global Clock Distribution Network

## Delay-Locked Loop (DLL)

Associated with each global clock input buffer is a fully digital Delay-Locked Loop (DLL) that can eliminate skew between the clock input pad and internal clock-input pins throughout the device. Each DLL can drive two global clock

networks. The DLL monitors the input clock and the distributed clock, and automatically adjusts a clock delay element. Additional delay is introduced such that clock edges reach internal flip-flops exactly one clock period after they arrive at the input. This closed-loop system effectively eliminates clock-distribution delay by ensuring that clock edges arrive at internal flip-flops in synchronism with clock edges arriving at the input.

In addition to eliminating clock-distribution delay, the DLL provides advanced control of multiple clock domains. The DLL provides four quadrature phases of the source clock, can double the clock, or divide the clock by 1.5, 2, 2.5, 3, 4, 5, 8, or 16. It has six outputs.

The DLL also operates as a clock mirror. By driving the output from a DLL off-chip and then back on again, the DLL can be used to deskew a board level clock among multiple Spartan-II devices.

In order to guarantee that the system clock is operating correctly prior to the FPGA starting up after configuration, the DLL can delay the completion of the configuration process until after it has achieved lock.

## Boundary Scan

Spartan-II devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, SAMPLE/PRELOAD, and BYPASS instructions. The TAP also supports two USERCODE instructions and internal scan chains.

The TAP uses dedicated package pins that always operate using LVTTTL. For TDO to operate using LVTTTL, the  $V_{CCO}$  for Bank 2 must be 3.3V. Otherwise, TDO switches rail-to-rail between ground and  $V_{CCO}$ . TDI, TMS, and TCK have a default internal weak pull-up resistor, and TDO has no default resistor. Bitstream options allow setting any of the four TAP pins to have an internal pull-up, pull-down, or neither.

By default, these operations are synchronized to CCLK. The entire start-up sequence lasts eight cycles, called C0-C7, after which the loaded design is fully functional. The default timing for start-up is shown in the top half of Figure 13. The four operations can be selected to switch on any CCLK cycle C1-C6 through settings in the Xilinx software. Heavy lines show default settings.

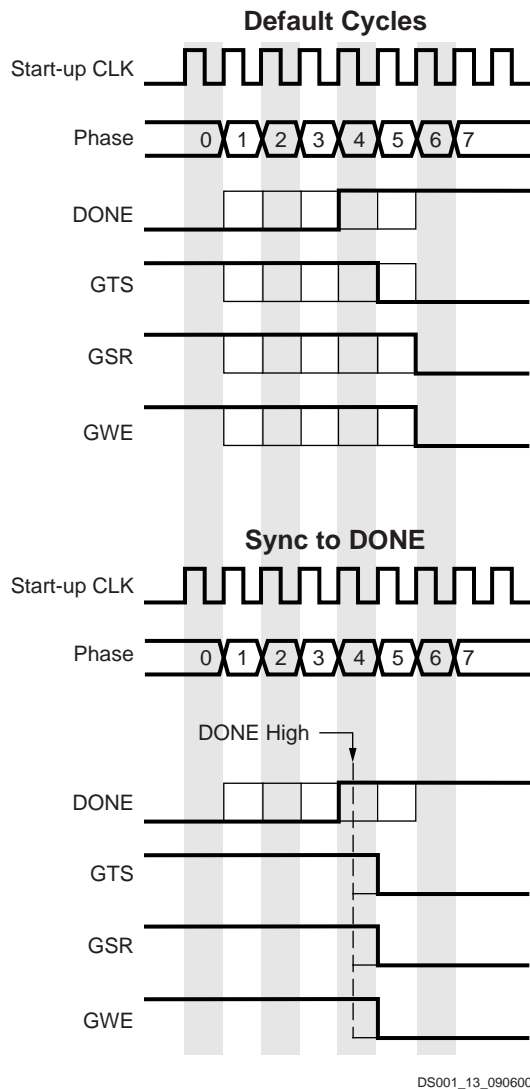


Figure 13: Start-Up Waveforms

The bottom half of Figure 13 shows another commonly used version of the start-up timing known as Sync-to-DONE. This version makes the GTS, GSR, and GWE events conditional upon the DONE pin going High. This timing is important for a daisy chain of multiple FPGAs in serial mode, since it ensures that all FPGAs go through start-up together, after all their DONE pins have gone High.

Sync-to-DONE timing is selected by setting the GTS, GSR, and GWE cycles to a value of DONE in the configuration options. This causes these signals to transition one clock cycle after DONE externally transitions High.

## Serial Modes

There are two serial configuration modes: In Master Serial mode, the FPGA controls the configuration process by driving CCLK as an output. In Slave Serial mode, the FPGA passively receives CCLK as an input from an external agent (e.g., a microprocessor, CPLD, or second FPGA in master mode) that is controlling the configuration process. In both modes, the FPGA is configured by loading one bit per CCLK cycle. The MSB of each configuration data byte is always written to the DIN pin first.

See Figure 14 for the sequence for loading data into the Spartan-II FPGA serially. This is an expansion of the "Load Configuration Data Frames" block in Figure 11. Note that CS and WRITE normally are not used during serial configuration. To ensure successful loading of the FPGA, do not toggle WRITE with CS Low during serial configuration.

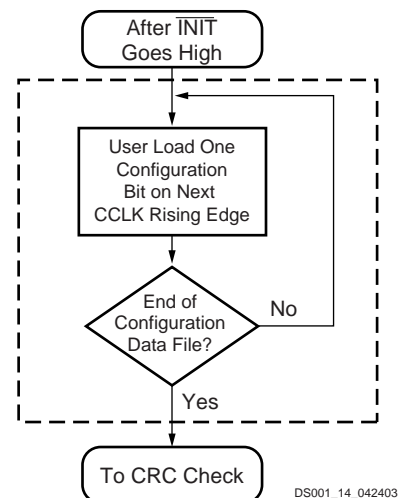


Figure 14: Loading Serial Mode Configuration Data

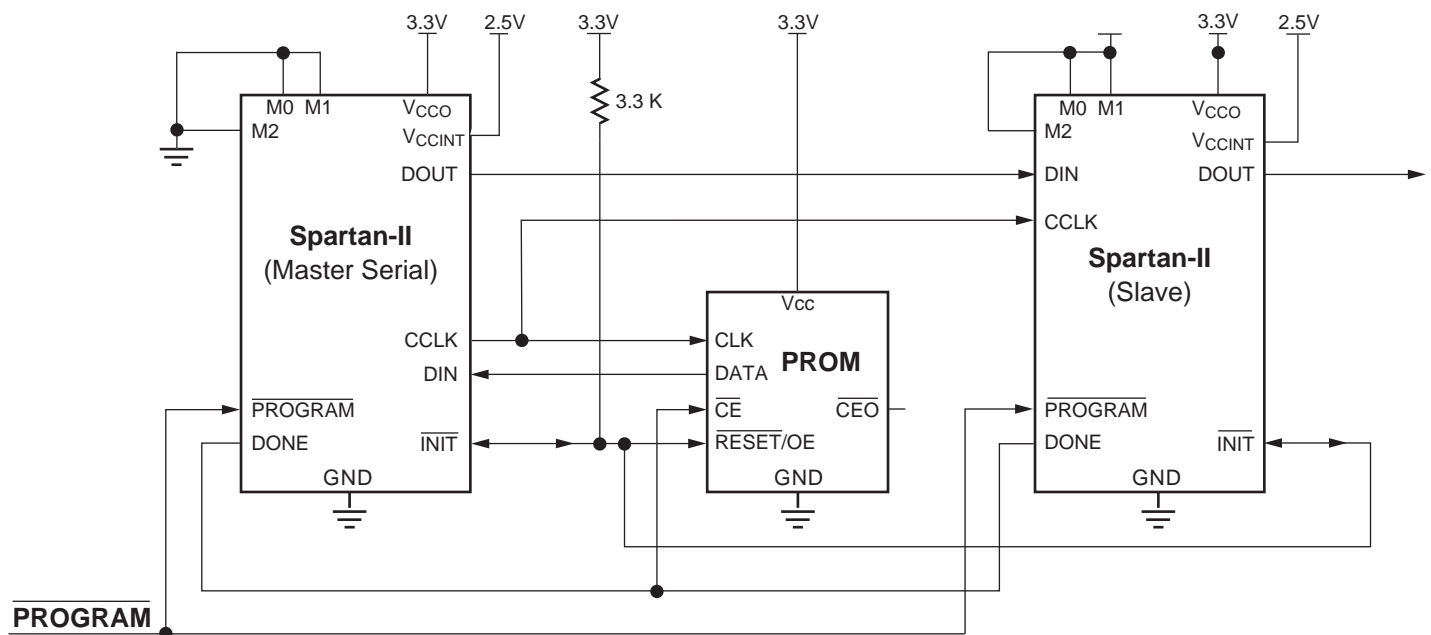
## Slave Serial Mode

In Slave Serial mode, the FPGA's CCLK pin is driven by an external source, allowing FPGAs to be configured from other logic devices such as microprocessors or in a daisy-chain configuration. Figure 15 shows connections for a Master Serial FPGA configuring a Slave Serial FPGA from a PROM. A Spartan-II device in slave serial mode should be connected as shown for the third device from the left. Slave Serial mode is selected by a <11x> on the mode pins (M0, M1, M2).

Figure 16 shows the timing for Slave Serial configuration. The serial bitstream must be setup at the DIN input pin a short time before each rising edge of an externally generated CCLK.

Multiple FPGAs in Slave Serial mode can be daisy-chained for configuration from a single source. The maximum amount of data that can be sent to the DOUT pin for a serial daisy chain is  $2^{20}-1$  (1,048,575) 32-bit words, or 33,554,400 bits, which is approximately 25 XC2S200 bitstreams. The configuration bitstream of downstream devices is limited to this size.

After an FPGA is configured, data for the next device is routed to the DOUT pin. Data on the DOUT pin changes on the rising edge of CCLK. Configuration must be delayed until INIT pins of all daisy-chained FPGAs are High. For more information, see "Start-up," page 19.

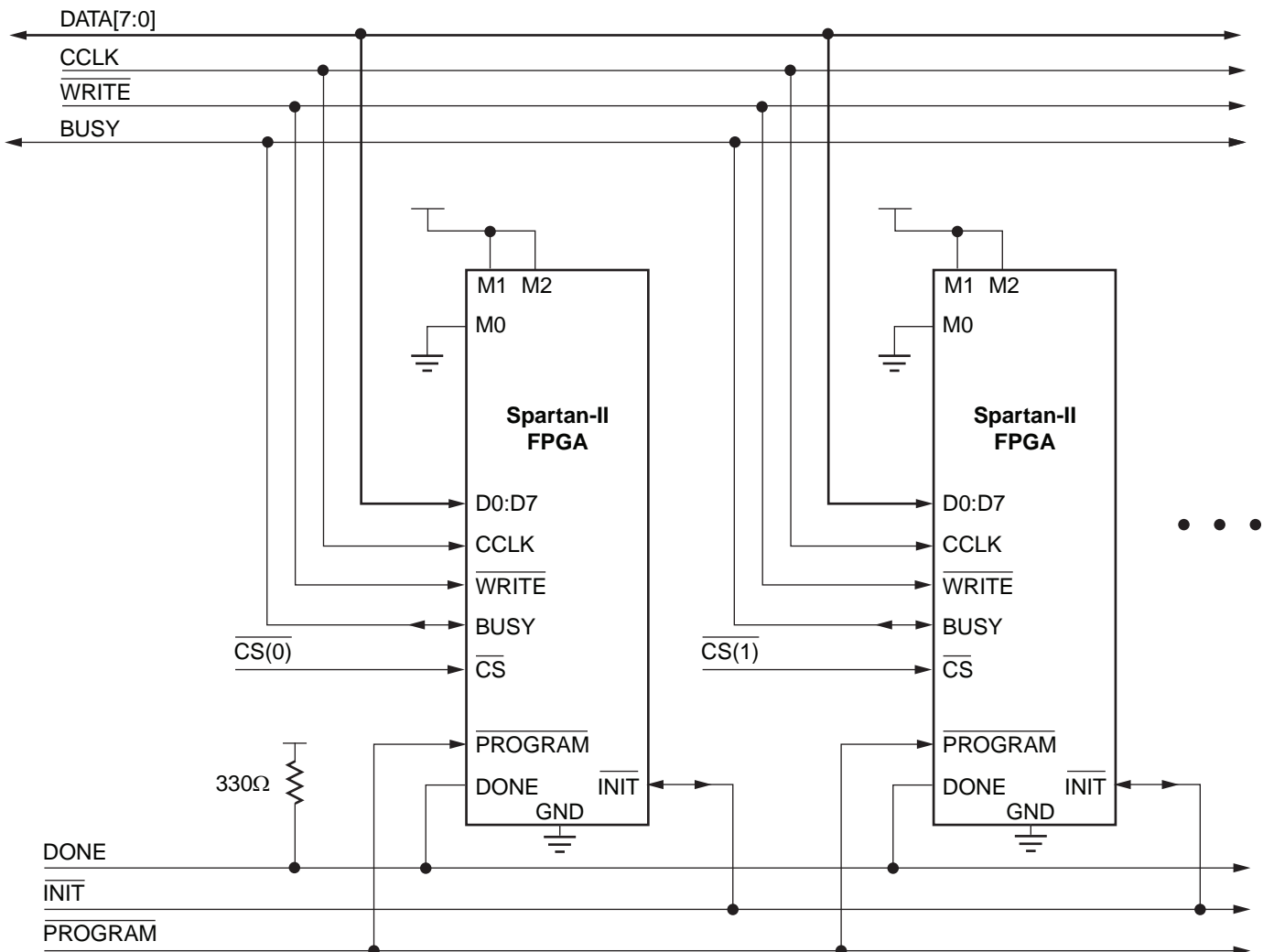


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### Notes:

1. If the DriveDone configuration option is not active for any of the FPGAs, pull up DONE with a 330Ω resistor.

Figure 15: Master/Slave Serial Configuration Circuit Diagram



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Figure 18: Slave Parallel Configuration Circuit Diagram

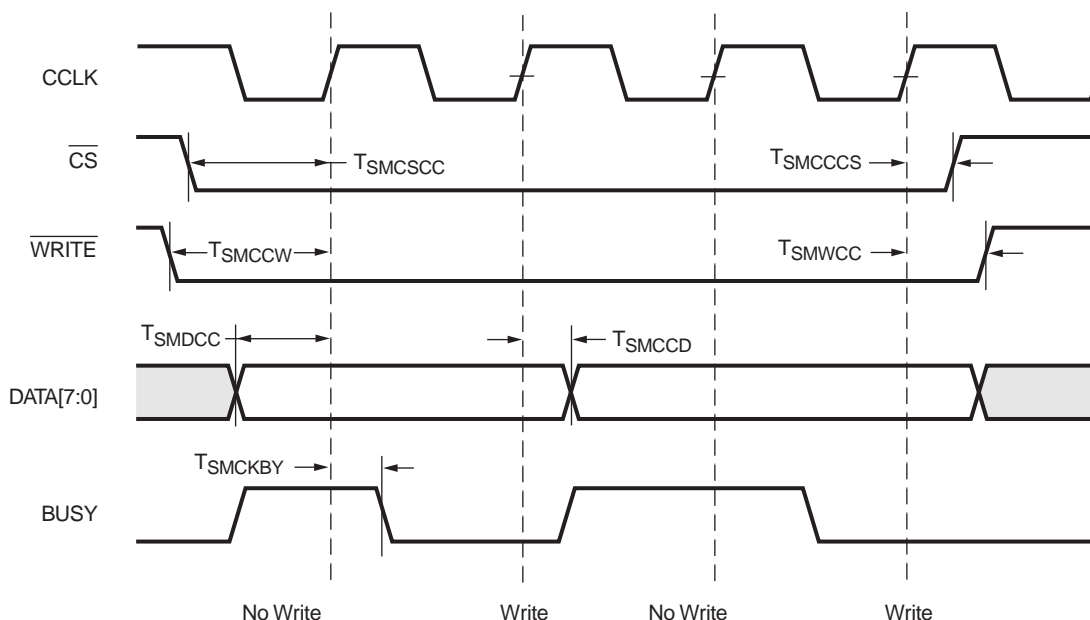
Multiple Spartan-II FPGAs can be configured using the Slave Parallel mode, and be made to start-up simultaneously. To configure multiple devices in this way, wire the individual CCLK, Data,  $\overline{\text{WRITE}}$ , and BUSY pins of all the devices in parallel. The individual devices are loaded separately by asserting the  $\overline{\text{CS}}$  pin of each device in turn and writing the appropriate data. Sync-to-DONE start-up timing is used to ensure that the start-up sequence does not begin until all the FPGAs have been loaded. See "Start-up," page 19.

### Write

When using the Slave Parallel Mode, write operations send packets of byte-wide configuration data into the FPGA. Figure 19, page 25 shows a flowchart of the write sequence used to load data into the Spartan-II FPGA. This is an expansion of the "Load Configuration Data Frames" block in Figure 11, page 18. The timing for write operations is shown in Figure 20, page 26.

For the present example, the user holds  $\overline{\text{WRITE}}$  and  $\overline{\text{CS}}$  Low throughout the sequence of write operations. Note that when  $\overline{\text{CS}}$  is asserted on successive CCLKs,  $\overline{\text{WRITE}}$  must remain either asserted or de-asserted. Otherwise an abort will be initiated, as in the next section.

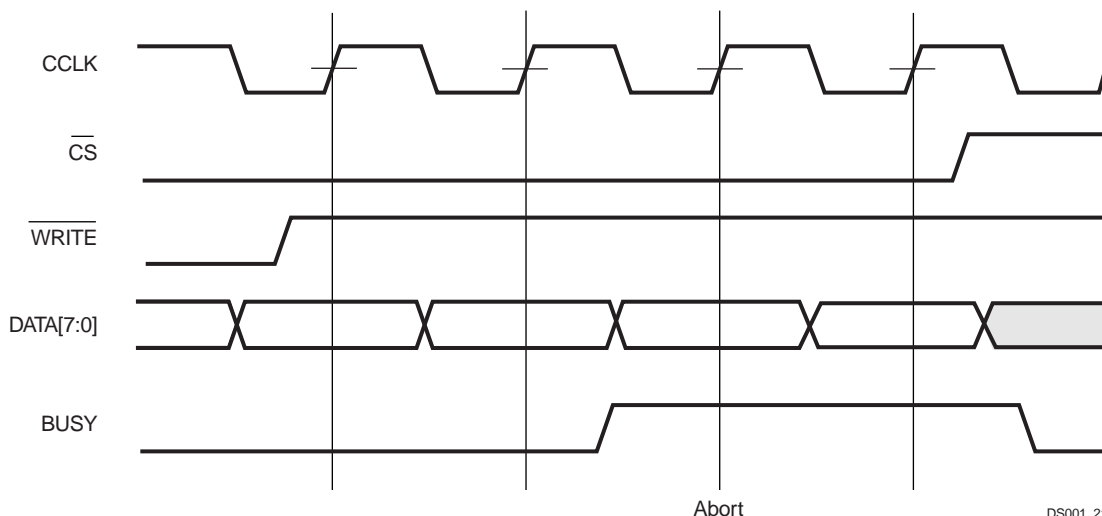
1. Drive data onto D0:D7. Note that to avoid contention, the data source should not be enabled while  $\overline{\text{CS}}$  is Low and  $\overline{\text{WRITE}}$  is High. Similarly, while  $\overline{\text{WRITE}}$  is High, no more than one device's  $\overline{\text{CS}}$  should be asserted.
2. On the rising edge of CCLK: If BUSY is Low, the data is accepted on this clock. If BUSY is High (from a previous write), the data is not accepted. Acceptance will instead occur on the first clock after BUSY goes Low, and the data must be held until this happens.
3. Repeat steps 1 and 2 until all the data has been sent.
4. De-assert  $\overline{\text{CS}}$  and  $\overline{\text{WRITE}}$ .



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Symbol		Description		Units
$T_{SMDCC}$	CCLK	D0-D7 setup/hold	5	ns, min
$T_{SMCCD}$		D0-D7 hold	0	ns, min
$T_{SMCSCC}$		$\overline{CS}$ setup	7	ns, min
$T_{SMCCCS}$		$\overline{CS}$ hold	0	ns, min
$T_{SMCCW}$		$\overline{WRITE}$ setup	7	ns, min
$T_{SMWCC}$		$\overline{WRITE}$ hold	0	ns, min
$T_{SMCKBY}$		BUSY propagation delay	12	ns, max
$F_{CC}$		Maximum frequency	66	MHz, max
$F_{CCNH}$		Maximum frequency with no handshake	50	MHz, max

Figure 20: Slave Parallel Write Timing



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Figure 21: Slave Parallel Write Abort Waveforms

## LVTTL

LVTTL requires no termination. DC voltage specifications appears in [Table 32](#) for the LVTTL standard. See "[DC Specifications](#)" in Module 3 for the actual FPGA characteristics.

Table 32: LVTTL Voltage Specifications

Parameter	Min	Typ	Max
$V_{CCO}$	3.0	3.3	3.6
$V_{REF}$	-	-	-
$V_{TT}$	-	-	-
$V_{IH}$	2.0	-	5.5
$V_{IL}$	-0.5	-	0.8
$V_{OH}$	2.4	-	-
$V_{OL}$	-	-	0.4
$I_{OH}$ at $V_{OH}$ (mA)	-24	-	-
$I_{OL}$ at $V_{OL}$ (mA)	24	-	-

### Notes:

1.  $V_{OL}$  and  $V_{OH}$  for lower drive currents sample tested.

## LVC MOS2

LVC MOS2 requires no termination. DC voltage specifications appear in [Table 33](#) for the LVC MOS2 standard. See "[DC Specifications](#)" in Module 3 for the actual FPGA characteristics.

Table 33: LVC MOS2 Voltage Specifications

Parameter	Min	Typ	Max
$V_{CCO}$	2.3	2.5	2.7
$V_{REF}$	-	-	-
$V_{TT}$	-	-	-
$V_{IH}$	1.7	-	5.5
$V_{IL}$	-0.5	-	0.7
$V_{OH}$	1.9	-	-
$V_{OL}$	-	-	0.4
$I_{OH}$ at $V_{OH}$ (mA)	-12	-	-
$I_{OL}$ at $V_{OL}$ (mA)	12	-	-

## AGP-2X

The specification for the AGP-2X standard does not document a recommended termination technique. DC voltage specifications appear in [Table 34](#) for the AGP-2X standard. See "[DC Specifications](#)" in Module 3 for the actual FPGA characteristics.

Table 34: AGP-2X Voltage Specifications

Parameter	Min	Typ	Max
$V_{CCO}$	3.0	3.3	3.6
$V_{REF} = N \times V_{CCO}^{(1)}$	1.17	1.32	1.48
$V_{TT}$	-	-	-
$V_{IH} \geq V_{REF} + 0.2$	1.37	1.52	-
$V_{IL} \leq V_{REF} - 0.2$	-	1.12	1.28
$V_{OH} \geq 0.9 \times V_{CCO}$	2.7	3.0	-
$V_{OL} \leq 0.1 \times V_{CCO}$	-	0.33	0.36
$I_{OH}$ at $V_{OH}$ (mA)	Note 2	-	-
$I_{OL}$ at $V_{OL}$ (mA)	Note 2	-	-

### Notes:

1. N must be greater than or equal to 0.39 and less than or equal to 0.41.
2. Tested according to the relevant specification.

For design examples and more information on using the I/O, see [XAPP179](#), *Using SelectIO Interfaces in Spartan-II and Spartan-IIe FPGAs*.

## Definition of Terms

In this document, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

**Advance:** Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or families. Values are subject to change. Use as estimates, not for production.

**Preliminary:** Based on preliminary characterization. Further changes are not expected.

**Unmarked:** Specifications not identified as either Advance or Preliminary are to be considered Final.

Except for pin-to-pin input and output parameters, the AC parameter delay specifications included in this document are derived from measuring internal test patterns. All limits are representative of worst-case supply voltage and junction temperature conditions. Typical numbers are based on measurements taken at a nominal  $V_{CCINT}$  level of 2.5V and a junction temperature of 25°C. The parameters included are common to popular designs and typical applications. **All specifications are subject to change without notice.**

## DC Specifications

### Absolute Maximum Ratings<sup>(1)</sup>

Symbol	Description	Min	Max	Units
$V_{CCINT}$	Supply voltage relative to GND <sup>(2)</sup>	-0.5	3.0	V
$V_{CCO}$	Supply voltage relative to GND <sup>(2)</sup>	-0.5	4.0	V
$V_{REF}$	Input reference voltage	-0.5	3.6	V
$V_{IN}$	Input voltage relative to GND <sup>(3)</sup>			
	5V tolerant I/O <sup>(4)</sup>	-0.5	5.5	V
$V_{TS}$	Input voltage relative to GND <sup>(3)</sup>			
	No 5V tolerance <sup>(5)</sup>	-0.5	$V_{CCO} + 0.5$	V
$V_{TS}$	Voltage applied to 3-state output			
	5V tolerant I/O <sup>(4)</sup>	-0.5	5.5	V
$V_{TS}$	Voltage applied to 3-state output			
	No 5V tolerance <sup>(5)</sup>	-0.5	$V_{CCO} + 0.5$	V
$T_{STG}$	Storage temperature (ambient)	-65	+150	°C
$T_J$	Junction temperature	-	+125	°C

#### Notes:

- Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.
- Power supplies may turn on in any order.
- $V_{IN}$  should not exceed  $V_{CCO}$  by more than 3.6V over extended periods of time (e.g., longer than a day).
- Spartan®-II device I/Os are 5V Tolerant whenever the LVTTTL, LVCMOS2, or PCI33\_5 signal standard has been selected. With 5V Tolerant I/Os selected, the Maximum DC overshoot must be limited to either +5.5V or 10 mA, and undershoot must be limited to either -0.5V or 10 mA, whichever is easier to achieve. The Maximum AC conditions are as follows: The device pins may undershoot to -2.0V or overshoot to +7.0V, provided this over/undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
- Without 5V Tolerant I/Os selected, the Maximum DC overshoot must be limited to either  $V_{CCO} + 0.5V$  or 10 mA, and undershoot must be limited to -0.5V or 10 mA, whichever is easier to achieve. The Maximum AC conditions are as follows: The device pins may undershoot to -2.0V or overshoot to  $V_{CCO} + 2.0V$ , provided this over/undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
- For soldering guidelines, see the [Packaging Information](#) on the Xilinx® web site.

## Power-On Requirements

Spartan-II FPGAs require that a minimum supply current  $I_{CCPO}$  be provided to the  $V_{CCINT}$  lines for a successful power-on. If more current is available, the FPGA can consume more than  $I_{CCPO}$  minimum, though this cannot adversely affect reliability.

A maximum limit for  $I_{CCPO}$  is not specified. Therefore the use of foldback/crowbar supplies and fuses deserves special attention. In these cases, limit the  $I_{CCPO}$  current to a level below the trip point for over-current protection in order to avoid inadvertently shutting down the supply.

Symbol	Description	Conditions		New Requirements <sup>(1)</sup> For Devices with Date Code 0321 or Later		Old Requirements <sup>(1)</sup> For Devices with Date Code before 0321		Units
		Junction Temperature <sup>(2)</sup>	Device Temperature Grade	Min	Max	Min	Max	
$I_{CCPO}$ <sup>(3)</sup>	Total $V_{CCINT}$ supply current required during power-on	$-40^{\circ}\text{C} \leq T_J < -20^{\circ}\text{C}$	Industrial	1.50	-	2.00	-	A
		$-20^{\circ}\text{C} \leq T_J < 0^{\circ}\text{C}$	Industrial	1.00	-	2.00	-	A
		$0^{\circ}\text{C} \leq T_J \leq 85^{\circ}\text{C}$	Commercial	0.25	-	0.50	-	A
		$85^{\circ}\text{C} < T_J \leq 100^{\circ}\text{C}$	Industrial	0.50	-	0.50	-	A
$T_{CCPO}$ <sup>(4,5)</sup>	$V_{CCINT}$ ramp time	$-40^{\circ}\text{C} \leq T_J \leq 100^{\circ}\text{C}$	All	-	50	-	50	ms

### Notes:

- The date code is printed on the top of the device's package. See the "Device Part Marking" section in Module 1.
- The expected  $T_J$  range for the design determines the  $I_{CCPO}$  minimum requirement. Use the applicable ranges in the junction temperature column to find the associated current values in the appropriate new or old requirements column according to the date code. Then choose the highest of these current values to serve as the minimum  $I_{CCPO}$  requirement that must be met. For example, if the junction temperature for a given design is  $-25^{\circ}\text{C} \leq T_J \leq 75^{\circ}\text{C}$ , then the new minimum  $I_{CCPO}$  requirement is 1.5A. If  $5^{\circ}\text{C} \leq T_J \leq 90^{\circ}\text{C}$ , then the new minimum  $I_{CCPO}$  requirement is 0.5A.
- The  $I_{CCPO}$  requirement applies for a brief time (commonly only a few milliseconds) when  $V_{CCINT}$  ramps from 0 to 2.5V.
- The ramp time is measured from GND to  $V_{CCINT}$  max on a fully loaded board.
- During power-on, the  $V_{CCINT}$  ramp must increase steadily in voltage with no dips.
- For more information on designing to meet the power-on specifications, refer to the application note [XAPP450 "Power-On Current Requirements for the Spartan-II and Spartan-II-E Families"](#)

## DC Input and Output Levels

Values for  $V_{IL}$  and  $V_{IH}$  are recommended input voltages. Values for  $V_{OL}$  and  $V_{OH}$  are guaranteed output voltages over the recommended operating conditions. Only selected standards are tested. These are chosen to ensure that all

standards meet their specifications. The selected standards are tested at minimum  $V_{CCO}$  with the respective  $I_{OL}$  and  $I_{OH}$  currents shown. Other standards are sample tested.

Input/Output Standard	$V_{IL}$		$V_{IH}$		$V_{OL}$	$V_{OH}$	$I_{OL}$	$I_{OH}$
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
LVTTL <sup>(1)</sup>	-0.5	0.8	2.0	5.5	0.4	2.4	24	-24
LVC MOS2	-0.5	0.7	1.7	5.5	0.4	1.9	12	-12
PCI, 3.3V	-0.5	44% $V_{CCINT}$	60% $V_{CCINT}$	$V_{CCO} + 0.5$	10% $V_{CCO}$	90% $V_{CCO}$	Note (2)	Note (2)
PCI, 5.0V	-0.5	0.8	2.0	5.5	0.55	2.4	Note (2)	Note (2)
GTL	-0.5	$V_{REF} - 0.05$	$V_{REF} + 0.05$	3.6	0.4	N/A	40	N/A
GTL+	-0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.6	N/A	36	N/A
HSTL I	-0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.4	$V_{CCO} - 0.4$	8	-8
HSTL III	-0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.4	$V_{CCO} - 0.4$	24	-8
HSTL IV	-0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.4	$V_{CCO} - 0.4$	48	-8
SSTL3 I	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.6$	$V_{REF} + 0.6$	8	-8
SSTL3 II	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.8$	$V_{REF} + 0.8$	16	-16
SSTL2 I	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.6$	$V_{REF} + 0.6$	7.6	-7.6
SSTL2 II	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.8$	$V_{REF} + 0.8$	15.2	-15.2

Input/Output Standard	$V_{IL}$		$V_{IH}$		$V_{OL}$	$V_{OH}$	$I_{OL}$	$I_{OH}$
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
CTT	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.4$	$V_{REF} + 0.4$	8	-8
AGP	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	10% $V_{CCO}$	90% $V_{CCO}$	Note (2)	Note (2)

**Notes:**

1.  $V_{OL}$  and  $V_{OH}$  for lower drive currents are sample tested.
2. Tested according to the relevant specifications.

## Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-II devices unless otherwise noted.

### Global Clock Input to Output Delay for LVTTL, with DLL (Pin-to-Pin)<sup>(1)</sup>

Symbol	Description	Device	Speed Grade			Units
			All	-6	-5	
			Min	Max	Max	
$T_{ICKOFDLL}$	Global clock input to output delay using output flip-flop for LVTTL, 12 mA, fast slew rate, <i>with</i> DLL.	All		2.9	3.3	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see the tables ["Constants for Calculating TIOOP"](#) and ["Delay Measurement Methodology,"](#) page 60.
3. DLL output jitter is already included in the timing calculation.
4. For data *output* with different standards, adjust delays with the values shown in ["IOB Output Delay Adjustments for Different Standards,"](#) page 59. For a global clock input with standards other than LVTTL, adjust delays with values from the ["I/O Standard Global Clock Input Adjustments,"](#) page 61.

### Global Clock Input to Output Delay for LVTTL, without DLL (Pin-to-Pin)<sup>(1)</sup>

Symbol	Description	Device	Speed Grade			Units
			All	-6	-5	
			Min	Max	Max	
$T_{ICKOF}$	Global clock input to output delay using output flip-flop for LVTTL, 12 mA, fast slew rate, <i>without</i> DLL.	XC2S15		4.5	5.4	ns
		XC2S30		4.5	5.4	ns
		XC2S50		4.5	5.4	ns
		XC2S100		4.6	5.5	ns
		XC2S150		4.6	5.5	ns
		XC2S200		4.7	5.6	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see the tables ["Constants for Calculating TIOOP"](#) and ["Delay Measurement Methodology,"](#) page 60.
3. For data *output* with different standards, adjust delays with the values shown in ["IOB Output Delay Adjustments for Different Standards,"](#) page 59. For a global clock input with standards other than LVTTL, adjust delays with values from the ["I/O Standard Global Clock Input Adjustments,"](#) page 61.

## IOB Input Switching Characteristics<sup>(1)</sup>

Input delays associated with the pad are specified for LVTTTL levels. For other standards, adjust the delays with the values shown in "IOB Input Delay Adjustments for Different Standards," page 57.

Symbol	Description	Device	Speed Grade				Units
			-6		-5		
			Min	Max	Min	Max	
Propagation Delays							
T <sub>IOPI</sub>	Pad to I output, no delay	All	-	0.8	-	1.0	ns
T <sub>IOPID</sub>	Pad to I output, with delay	All	-	1.5	-	1.8	ns
T <sub>IOPLI</sub>	Pad to output IQ via transparent latch, no delay	All	-	1.7	-	2.0	ns
T <sub>IOPLID</sub>	Pad to output IQ via transparent latch, with delay	XC2S15	-	3.8	-	4.5	ns
		XC2S30	-	3.8	-	4.5	ns
		XC2S50	-	3.8	-	4.5	ns
		XC2S100	-	3.8	-	4.5	ns
		XC2S150	-	4.0	-	4.7	ns
		XC2S200	-	4.0	-	4.7	ns
Sequential Delays							
T <sub>IOCKIQ</sub>	Clock CLK to output IQ	All	-	0.7	-	0.8	ns
Setup/Hold Times with Respect to Clock CLK <sup>(2)</sup>							
T <sub>IOPICK</sub> / T <sub>IOICKP</sub>	Pad, no delay	All	1.7 / 0	-	1.9 / 0	-	ns
T <sub>IOPICKD</sub> / T <sub>IOICKPD</sub>	Pad, with delay <sup>(1)</sup>	XC2S15	3.8 / 0	-	4.4 / 0	-	ns
		XC2S30	3.8 / 0	-	4.4 / 0	-	ns
		XC2S50	3.8 / 0	-	4.4 / 0	-	ns
		XC2S100	3.8 / 0	-	4.4 / 0	-	ns
		XC2S150	3.9 / 0	-	4.6 / 0	-	ns
		XC2S200	3.9 / 0	-	4.6 / 0	-	ns
T <sub>IOICECK</sub> / T <sub>IOICKICE</sub>	ICE input	All	0.9 / 0.01	-	0.9 / 0.01	-	ns
Set/Reset Delays							
T <sub>IOSRCKI</sub>	SR input (IFF, synchronous)	All	-	1.1	-	1.2	ns
T <sub>IOSRIQ</sub>	SR input to IQ (asynchronous)	All	-	1.5	-	1.7	ns
T <sub>GSRQ</sub>	GSR to output IQ	All	-	9.9	-	11.7	ns

### Notes:

- Input timing for LVTTTL is measured at 1.4V. For other I/O standards, see the table "Delay Measurement Methodology," page 60.
- A zero hold time listing indicates no hold time or a negative hold time.

## DLL Timing Parameters

All devices are 100 percent functionally tested. Because of the difficulty in directly measuring many internal timing parameters, those parameters are derived from benchmark

timing patterns. The following guidelines reflect worst-case values across the recommended operating conditions.

Symbol	Description	Speed Grade				Units
		-6		-5		
		Min	Max	Min	Max	
F <sub>CLKINHF</sub>	Input clock frequency (CLKDLLHF)	60	200	60	180	MHz
F <sub>CLKINLF</sub>	Input clock frequency (CLKDLL)	25	100	25	90	MHz
T <sub>DLLPWHF</sub>	Input clock pulse width (CLKDLLHF)	2.0	-	2.4	-	ns
T <sub>DLLPWL</sub>	Input clock pulse width (CLKDLL)	2.5	-	3.0	-	ns

## DLL Clock Tolerance, Jitter, and Phase Information

All DLL output jitter and phase specifications were determined through statistical measurement at the package pins using a clock mirror configuration and matched drivers.

Figure 52, page 63, provides definitions for various parameters in the table below.

Symbol	Description	F <sub>CLKIN</sub>	CLKDLLHF		CLKDLL		Units
			Min	Max	Min	Max	
T <sub>IPTOL</sub>	Input clock period tolerance		-	1.0	-	1.0	ns
T <sub>IJITCC</sub>	Input clock jitter tolerance (cycle-to-cycle)		-	±150	-	±300	ps
T <sub>LOCK</sub>	Time required for DLL to acquire lock	> 60 MHz	-	20	-	20	μs
		50-60 MHz	-	-	-	25	μs
		40-50 MHz	-	-	-	50	μs
		30-40 MHz	-	-	-	90	μs
		25-30 MHz	-	-	-	120	μs
T <sub>OJITCC</sub>	Output jitter (cycle-to-cycle) for any DLL clock output <sup>(1)</sup>		-	±60	-	±60	ps
T <sub>PHIO</sub>	Phase offset between CLKIN and CLKO <sup>(2)</sup>		-	±100	-	±100	ps
T <sub>PHOO</sub>	Phase offset between clock outputs on the DLL <sup>(3)</sup>		-	±140	-	±140	ps
T <sub>PHIOM</sub>	Maximum phase difference between CLKIN and CLKO <sup>(4)</sup>		-	±160	-	±160	ps
T <sub>PHOOM</sub>	Maximum phase difference between clock outputs on the DLL <sup>(5)</sup>		-	±200	-	±200	ps

### Notes:

- Output Jitter** is cycle-to-cycle jitter measured on the DLL output clock, *excluding* input clock jitter.
- Phase Offset between CLKIN and CLKO** is the worst-case fixed time difference between rising edges of CLKIN and CLKO, *excluding* output jitter and input clock jitter.
- Phase Offset between Clock Outputs on the DLL** is the worst-case fixed time difference between rising edges of any two DLL outputs, *excluding* Output Jitter and input clock jitter.
- Maximum Phase Difference between CLKIN and CLKO** is the sum of Output Jitter and Phase Offset between CLKIN and CLKO, or the greatest difference between CLKIN and CLKO rising edges due to DLL alone (*excluding* input clock jitter).
- Maximum Phase Difference between Clock Outputs on the DLL** is the sum of Output Jitter and Phase Offset between any DLL clock outputs, or the greatest difference between any two DLL output rising edges due to DLL alone (*excluding* input clock jitter).

## Package Thermal Characteristics

Table 39 provides the thermal characteristics for the various Spartan-II FPGA package offerings. This information is also available using the Thermal Query tool on [www.xilinx.com](http://www.xilinx.com/cgi-bin/thermal/thermal.pl) ([www.xilinx.com/cgi-bin/thermal/thermal.pl](http://www.xilinx.com/cgi-bin/thermal/thermal.pl)).

The junction-to-case thermal resistance ( $\theta_{JC}$ ) indicates the difference between the temperature measured on the package body (case) and the die junction temperature per watt of power consumption. The junction-to-board ( $\theta_{JB}$ )

value similarly reports the difference between the board and junction temperature. The junction-to-ambient ( $\theta_{JA}$ ) value reports the temperature difference between the ambient environment and the junction temperature. The  $\theta_{JA}$  value is reported at different air velocities, measured in linear feet per minute (LFM). The “Still Air (0 LFM)” column shows the  $\theta_{JA}$  value in a system without a fan. The thermal resistance drops with increasing air flow.

Table 39: Spartan-II Package Thermal Characteristics

Package	Device	Junction-to-Case ( $\theta_{JC}$ )	Junction-to-Board ( $\theta_{JB}$ )	Junction-to-Ambient ( $\theta_{JA}$ ) at Different Air Flows				Units
				Still Air (0 LFM)	250 LFM	500 LFM	750 LFM	
VQ100 VQG100	XC2S15	11.3	N/A	44.1	36.7	34.2	33.3	°C/Watt
	XC2S30	10.1	N/A	40.7	33.9	31.5	30.8	°C/Watt
TQ144 TQG144	XC2S15	7.3	N/A	38.6	30.0	25.7	24.1	°C/Watt
	XC2S30	6.7	N/A	34.7	27.0	23.1	21.7	°C/Watt
	XC2S50	5.8	N/A	32.2	25.1	21.4	20.1	°C/Watt
	XC2S100	5.3	N/A	31.4	24.4	20.9	19.6	°C/Watt
CS144 CSG144	XC2S30	2.8	N/A	34.0	26.0	23.9	23.2	°C/Watt
PQ208 PQG208	XC2S50	6.7	N/A	25.2	18.6	16.4	15.2	°C/Watt
	XC2S100	5.9	N/A	24.6	18.1	16.0	14.9	°C/Watt
	XC2S150	5.0	N/A	23.8	17.6	15.6	14.4	°C/Watt
	XC2S200	4.1	N/A	23.0	17.0	15.0	13.9	°C/Watt
FG256 FGG256	XC2S50	7.1	17.6	27.2	21.4	20.3	19.8	°C/Watt
	XC2S100	5.8	15.1	25.1	19.5	18.3	17.8	°C/Watt
	XC2S150	4.6	12.7	23.0	17.6	16.3	15.8	°C/Watt
	XC2S200	3.5	10.7	21.4	16.1	14.7	14.2	°C/Watt
FG456 FGG456	XC2S150	2.0	N/A	21.9	17.3	15.8	15.2	°C/Watt
	XC2S200	2.0	N/A	21.0	16.6	15.1	14.5	°C/Watt

## Pinout Tables

The following device-specific pinout tables include all packages available for each Spartan®-II device. They follow the pad locations around the die, and include Boundary Scan register locations.

### XC2S15 Device Pinouts

XC2S15 Pad Name		VQ100	TQ144	CS144	Bndry Scan
Function	Bank				
GND	-	P1	P143	A1	-
TMS	-	P2	P142	B1	-
I/O	7	P3	P141	C2	77
I/O	7	-	P140	C1	80
I/O, V <sub>REF</sub>	7	P4	P139	D4	83
I/O	7	P5	P137	D2	86
I/O	7	P6	P136	D1	89
GND	-	-	P135	E4	-
I/O	7	P7	P134	E3	92
I/O	7	-	P133	E2	95
I/O, V <sub>REF</sub>	7	P8	P132	E1	98
I/O	7	P9	P131	F4	101
I/O	7	-	P130	F3	104
I/O, IRDY <sup>(1)</sup>	7	P10	P129	F2	107
GND	-	P11	P128	F1	-
V <sub>CCO</sub>	7	P12	P127	G2	-
V <sub>CCO</sub>	6	P12	P127	G2	-
I/O, TRDY <sup>(1)</sup>	6	P13	P126	G1	110
V <sub>CCINT</sub>	-	P14	P125	G3	-
I/O	6	-	P124	G4	113
I/O	6	P15	P123	H1	116
I/O, V <sub>REF</sub>	6	P16	P122	H2	119
I/O	6	-	P121	H3	122
I/O	6	P17	P120	H4	125
GND	-	-	P119	J1	-
I/O	6	P18	P118	J2	128
I/O	6	P19	P117	J3	131
I/O, V <sub>REF</sub>	6	P20	P115	K1	134
I/O	6	-	P114	K2	137
I/O	6	P21	P113	K3	140
I/O	6	P22	P112	L1	143
M1	-	P23	P111	L2	146
GND	-	P24	P110	L3	-
M0	-	P25	P109	M1	147
V <sub>CCO</sub>	6	P26	P108	M2	-
V <sub>CCO</sub>	5	P26	P107	N1	-

### XC2S15 Device Pinouts (Continued)

XC2S15 Pad Name		VQ100	TQ144	CS144	Bndry Scan
Function	Bank				
M2	-	P27	P106	N2	148
I/O	5	-	P103	K4	155
I/O, V <sub>REF</sub>	5	P30	P102	L4	158
I/O	5	P31	P100	N4	161
I/O	5	P32	P99	K5	164
GND	-	-	P98	L5	-
V <sub>CCINT</sub>	-	P33	P97	M5	-
I/O	5	-	P96	N5	167
I/O	5	-	P95	K6	170
I/O, V <sub>REF</sub>	5	P34	P94	L6	173
I/O	5	-	P93	M6	176
V <sub>CCINT</sub>	-	P35	P92	N6	-
I, GCK1	5	P36	P91	M7	185
V <sub>CCO</sub>	5	P37	P90	N7	-
V <sub>CCO</sub>	4	P37	P90	N7	-
GND	-	P38	P89	L7	-
I, GCK0	4	P39	P88	K7	186
I/O	4	P40	P87	N8	190
I/O	4	-	P86	M8	193
I/O, V <sub>REF</sub>	4	P41	P85	L8	196
I/O	4	-	P84	K8	199
I/O	4	-	P83	N9	202
V <sub>CCINT</sub>	-	P42	P82	M9	-
GND	-	-	P81	L9	-
I/O	4	P43	P80	K9	205
I/O	4	P44	P79	N10	208
I/O, V <sub>REF</sub>	4	P45	P77	L10	211
I/O	4	-	P76	N11	214
I/O	4	P46	P75	M11	217
I/O	4	P47	P74	L11	220
GND	-	P48	P73	N12	-
DONE	3	P49	P72	M12	223
V <sub>CCO</sub>	4	P50	P71	N13	-
V <sub>CCO</sub>	3	P50	P70	M13	-
PROGRAM	-	P51	P69	L12	226
I/O (INIT)	3	P52	P68	L13	227
I/O (D7)	3	P53	P67	K10	230
I/O	3	-	P66	K11	233
I/O, V <sub>REF</sub>	3	P54	P65	K12	236
I/O	3	P55	P63	J10	239
I/O (D6)	3	P56	P62	J11	242

## XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
I/O	4	-	-	-	P87	295
I/O	4	-	-	-	P88	298
I/O	4	-	P84	K8	P89	301
I/O	4	-	P83	N9	P90	304
V <sub>CCINT</sub>	-	P42	P82	M9	P91	-
V <sub>CCO</sub>	4	-	-	-	P92	-
GND	-	-	P81	L9	P93	-
I/O	4	P43	P80	K9	P94	307
I/O	4	P44	P79	N10	P95	310
I/O	4	-	P78	M10	P96	313
I/O, V <sub>REF</sub>	4	P45	P77	L10	P98	316
I/O	4	-	-	-	P99	319
I/O	4	-	P76	N11	P100	322
I/O	4	P46	P75	M11	P101	325
I/O	4	P47	P74	L11	P102	328
GND	-	P48	P73	N12	P103	-
DONE	3	P49	P72	M12	P104	331
V <sub>CCO</sub>	4	P50	P71	N13	P105	-
V <sub>CCO</sub>	3	P50	P70	M13	P105	-
PROGRAM	-	P51	P69	L12	P106	334
I/O (INIT)	3	P52	P68	L13	P107	335
I/O (D7)	3	P53	P67	K10	P108	338
I/O	3	-	P66	K11	P109	341
I/O	3	-	-	-	P110	344
I/O, V <sub>REF</sub>	3	P54	P65	K12	P111	347
I/O	3	-	P64	K13	P113	350
I/O	3	P55	P63	J10	P114	353
I/O (D6)	3	P56	P62	J11	P115	356
GND	-	-	P61	J12	P116	-
V <sub>CCO</sub>	3	-	-	-	P117	-
I/O (D5)	3	P57	P60	J13	P119	359
I/O	3	P58	P59	H10	P120	362
I/O	3	-	-	-	P121	365
I/O	3	-	-	-	P122	368
I/O	3	-	-	-	P123	371
GND	-	-	-	-	P124	-
I/O, V <sub>REF</sub>	3	P59	P58	H11	P125	374
I/O (D4)	3	P60	P57	H12	P126	377
I/O	3	-	P56	H13	P127	380
V <sub>CCINT</sub>	-	P61	P55	G12	P128	-
I/O, TRDY <sup>(1)</sup>	3	P62	P54	G13	P129	386

## XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
V <sub>CCO</sub>	3	P63	P53	G11	P130	-
V <sub>CCO</sub>	2	P63	P53	G11	P130	-
GND	-	P64	P52	G10	P131	-
I/O, IRDY <sup>(1)</sup>	2	P65	P51	F13	P132	389
I/O	2	-	-	-	P133	392
I/O	2	-	P50	F12	P134	395
I/O (D3)	2	P66	P49	F11	P135	398
I/O, V <sub>REF</sub>	2	P67	P48	F10	P136	401
GND	-	-	-	-	P137	-
I/O	2	-	-	-	P138	404
I/O	2	-	-	-	P139	407
I/O	2	-	-	-	P140	410
I/O	2	P68	P47	E13	P141	413
I/O (D2)	2	P69	P46	E12	P142	416
V <sub>CCO</sub>	2	-	-	-	P144	-
GND	-	-	P45	E11	P145	-
I/O (D1)	2	P70	P44	E10	P146	419
I/O	2	P71	P43	D13	P147	422
I/O	2	-	P42	D12	P148	425
I/O, V <sub>REF</sub>	2	P72	P41	D11	P150	428
I/O	2	-	-	-	P151	431
I/O	2	-	P40	C13	P152	434
I/O (DIN, D0)	2	P73	P39	C12	P153	437
I/O (DOUT, BUSY)	2	P74	P38	C11	P154	440
CCLK	2	P75	P37	B13	P155	443
V <sub>CCO</sub>	2	P76	P36	B12	P156	-
V <sub>CCO</sub>	1	P76	P35	A13	P156	-
TDO	2	P77	P34	A12	P157	-
GND	-	P78	P33	B11	P158	-
TDI	-	P79	P32	A11	P159	-
I/O (CS)	1	P80	P31	D10	P160	0
I/O (WRITE)	1	P81	P30	C10	P161	3
I/O	1	-	P29	B10	P162	6
I/O	1	-	-	-	P163	9
I/O, V <sub>REF</sub>	1	P82	P28	A10	P164	12
I/O	1	-	-	-	P166	15
I/O	1	P83	P27	D9	P167	18
I/O	1	P84	P26	C9	P168	21
GND	-	-	P25	B9	P169	-
V <sub>CCO</sub>	1	-	-	-	P170	-

## XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name						
Function	Bank	TQ144	PQ208	FG256	FG456	Bndry Scan
I/O	2	-	-	F12	G20	695
I/O	2	-	P149	E15	F19	701
I/O, V <sub>REF</sub>	2	P41	P150	F13	F21	704
V <sub>CCO</sub>	2	-	-	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-
GND	-	-	-	GND*	GND*	-
I/O	2	-	P151	E14	F20	707
I/O	2	-	-	C16	F18	710
I/O	2	-	-	-	E21	713
I/O	2	P40	P152	E13	D22	716
I/O	2	-	-	B16	E20	719
I/O (DIN, DO)	2	P39	P153	D14	D20	725
I/O (DOUT, BUSY)	2	P38	P154	C15	C21	728
CCLK	2	P37	P155	D15	B22	731
V <sub>CCO</sub>	2	P36	P156	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-
V <sub>CCO</sub>	1	P35	P156	V <sub>CCO</sub> Bank 1*	V <sub>CCO</sub> Bank 1*	-
TDO	2	P34	P157	B14	A21	-
GND	-	P33	P158	GND*	GND*	-
TDI	-	P32	P159	A15	B20	-
I/O ( $\overline{\text{CS}}$ )	1	P31	P160	B13	C19	0
I/O ( $\overline{\text{WRITE}}$ )	1	P30	P161	C13	A20	3
I/O	1	-	-	C12	D17	9
I/O	1	P29	P162	A14	A19	12
I/O	1	-	-	-	B18	15
I/O	1	-	-	D12	C17	18
I/O	1	-	P163	B12	D16	21
GND	-	-	-	GND*	GND*	-
V <sub>CCO</sub>	1	-	-	V <sub>CCO</sub> Bank 1*	V <sub>CCO</sub> Bank 1*	-
I/O, V <sub>REF</sub>	1	P28	P164	C11	A18	24
I/O	1	-	P165	A13	B17	27
I/O	1	-	-	D11	D15	33
I/O	1	-	P166	A12	C16	36
I/O	1	-	-	-	D14	39
I/O, V <sub>REF</sub>	1	P27	P167	E11	E14	42
I/O	1	P26	P168	B11	A16	45
GND	-	P25	P169	GND*	GND*	-

## XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name						
Function	Bank	TQ144	PQ208	FG256	FG456	Bndry Scan
V <sub>CCO</sub>	1	-	P170	V <sub>CCO</sub> Bank 1*	V <sub>CCO</sub> Bank 1*	-
V <sub>CCINT</sub>	-	P24	P171	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O	1	P23	P172	A11	C15	48
I/O	1	P22	P173	C10	B15	51
I/O	1	-	-	-	F12	54
I/O	1	-	P174	B10	C14	57
I/O	1	-	P175	D10	D13	63
I/O	1	-	P176	A10	C13	66
GND	-	-	P177	GND*	GND*	-
I/O, V <sub>REF</sub>	1	P21	P178	B9	B13	69
I/O	1	-	P179	E10	E12	72
I/O	1	-	-	A9	B12	75
I/O	1	P20	P180	D9	D12	78
I/O	1	P19	P181	A8	D11	84
I, GCK2	1	P18	P182	C9	A11	90
GND	-	P17	P183	GND*	GND*	-
V <sub>CCO</sub>	1	P16	P184	V <sub>CCO</sub> Bank 1*	V <sub>CCO</sub> Bank 1*	-
V <sub>CCO</sub>	0	P16	P184	V <sub>CCO</sub> Bank 0*	V <sub>CCO</sub> Bank 0*	-
I, GCK3	0	P15	P185	B8	C11	91
V <sub>CCINT</sub>	-	P14	P186	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O	0	P13	P187	A7	A10	101
I/O	0	-	-	D8	B10	104

## Additional XC2S100 Package Pins

### TQ144

Not Connected Pins					
P104	P105	-	-	-	-

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### PQ208

Not Connected Pins					
P55	P56	-	-	-	-

11/02/00

### FG256

V <sub>CCINT</sub> Pins					
C3	C14	D4	D13	E5	E12
M5	M12	N4	N13	P3	P14
V <sub>CCO</sub> Bank 0 Pins					
E8	F8	-	-	-	-
V <sub>CCO</sub> Bank 1 Pins					
E9	F9	-	-	-	-
V <sub>CCO</sub> Bank 2 Pins					
H11	H12	-	-	-	-
V <sub>CCO</sub> Bank 3 Pins					
J11	J12	-	-	-	-
V <sub>CCO</sub> Bank 4 Pins					
L9	M9	-	-	-	-
V <sub>CCO</sub> Bank 5 Pins					
L8	M8	-	-	-	-
V <sub>CCO</sub> Bank 6 Pins					
J5	J6	-	-	-	-
V <sub>CCO</sub> Bank 7 Pins					
H5	H6	-	-	-	-
GND Pins					
A1	A16	B2	B15	F6	F7
F10	F11	G6	G7	G8	G9
G10	G11	H7	H8	H9	H10
J7	J8	J9	J10	K6	K7
K8	K9	K10	K11	L6	L7
L10	L11	R2	R15	T1	T16
Not Connected Pins					
P4	R4	-	-	-	-

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### FG456

V <sub>CCINT</sub> Pins					
E5	E18	F6	F17	G7	G8
G9	G14	G15	G16	H7	H16
J7	J16	P7	P16	R7	R16
T7	T8	T9	T14	T15	T16
U6	U17	V5	V18	-	-
V <sub>CCO</sub> Bank 0 Pins					

## Additional XC2S100 Package Pins (Continued)

F10	F7	F8	F9	G10	G11
V <sub>CCO</sub> Bank 1 Pins					
F13	F14	F15	F16	G12	G13
V <sub>CCO</sub> Bank 2 Pins					
G17	H17	J17	K16	K17	L16
V <sub>CCO</sub> Bank 3 Pins					
M16	N16	N17	P17	R17	T17
V <sub>CCO</sub> Bank 4 Pins					
T12	T13	U13	U14	U15	U16
V <sub>CCO</sub> Bank 5 Pins					
T10	T11	U10	U7	U8	U9
V <sub>CCO</sub> Bank 6 Pins					
M7	N6	N7	P6	R6	T6
V <sub>CCO</sub> Bank 7 Pins					
G6	H6	J6	K6	K7	L7
GND Pins					
A1	A22	B2	B21	C3	C20
J9	J10	J11	J12	J13	J14
K9	K10	K11	K12	K13	K14
L9	L10	L11	L12	L13	L14
M9	M10	M11	M12	M13	M14
N9	N10	N11	N12	N13	N14
P9	P10	P11	P12	P13	P14
Y3	Y20	AA2	AA21	AB1	AB22
Not Connected Pins					
A2	A4	A5	A6	A12	A13
A14	A15	A17	B3	B6	B8
B11	B14	B16	B19	C1	C2
C8	C9	C12	C18	C22	D1
D4	D5	D10	D18	D19	D21
E4	E11	E13	E15	E16	E17
E19	E22	F4	F11	F22	G2
G3	G4	G19	G22	H1	H21
J1	J3	J4	J19	J20	K2
K18	K19	L2	L5	L18	L19
M2	M6	M17	M18	M21	N1
N5	N19	P1	P5	P19	P22
R1	R3	R20	R22	T5	T19
U3	U11	U18	V1	V2	V10
V12	V17	V3	V4	V6	V8
V20	V21	V22	W4	W5	W9
W13	W14	W15	W16	W19	Y5
Y14	Y18	Y22	AA1	AA3	AA6
AA9	AA10	AA11	AA16	AA17	AA18
AA22	AB3	AB4	AB7	AB8	AB12
AB14	AB21	-	-	-	-

11/02/00

## XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	4	P90	R11	AA15	595
V <sub>CCINT</sub>	-	P91	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
V <sub>CCO</sub>	4	P92	V <sub>CCO</sub> Bank 4*	V <sub>CCO</sub> Bank 4*	-
GND	-	P93	GND*	GND*	-
I/O	4	P94	M11	Y15	598
I/O, V <sub>REF</sub>	4	P95	T11	AB16	601
I/O	4	-	-	AB17	604
I/O	4	P96	N11	V15	607
I/O	4	-	R12	Y16	610
I/O	4	-	-	AA17	613
I/O	4	-	-	W16	616
I/O	4	P97	P11	AB18	619
I/O, V <sub>REF</sub>	4	P98	T12	AB19	622
V <sub>CCO</sub>	4	-	V <sub>CCO</sub> Bank 4*	V <sub>CCO</sub> Bank 4*	-
GND	-	-	GND*	GND*	-
I/O	4	P99	T13	Y17	625
I/O	4	-	N12	V16	628
I/O	4	-	-	AA18	631
I/O	4	-	-	W17	634
I/O	4	P100	R13	AB20	637
GND	-	-	GND*	GND*	-
I/O	4	-	P12	AA19	640
I/O	4	-	-	V17	643
I/O	4	-	-	Y18	646
I/O	4	P101	P13	AA20	649
I/O	4	P102	T14	W18	652
GND	-	P103	GND*	GND*	-
DONE	3	P104	R14	Y19	655
V <sub>CCO</sub>	4	P105	V <sub>CCO</sub> Bank 4*	V <sub>CCO</sub> Bank 4*	-
V <sub>CCO</sub>	3	P105	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
PROGRAM	-	P106	P15	W20	658
I/O (INIT)	3	P107	N15	V19	659
I/O (D7)	3	P108	N14	Y21	662
I/O	3	-	-	V20	665
I/O	3	-	-	AA22	668
I/O	3	-	T15	W21	671
GND	-	-	GND*	GND*	-
I/O	3	P109	M13	U20	674

## XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	3	-	-	U19	677
I/O	3	-	-	V21	680
I/O	3	-	R16	T18	683
I/O	3	P110	M14	W22	686
GND	-	-	GND*	GND*	-
V <sub>CCO</sub>	3	-	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
I/O, V <sub>REF</sub>	3	P111	L14	U21	689
I/O	3	P112	M15	T20	692
I/O	3	-	-	T19	695
I/O	3	-	-	V22	698
I/O	3	-	L12	T21	701
I/O	3	P113	P16	R18	704
I/O	3	-	-	U22	707
I/O, V <sub>REF</sub>	3	P114	L13	R19	710
I/O (D6)	3	P115	N16	T22	713
GND	-	P116	GND*	GND*	-
V <sub>CCO</sub>	3	P117	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
V <sub>CCINT</sub>	-	P118	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O (D5)	3	P119	M16	R21	716
I/O	3	P120	K14	P18	719
I/O	3	-	-	P19	725
I/O	3	-	L16	P20	728
I/O	3	P121	K13	P21	731
I/O	3	-	-	N19	734
I/O	3	P122	L15	N18	740
I/O	3	P123	K12	N20	743
GND	-	P124	GND*	GND*	-
V <sub>CCO</sub>	3	-	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
I/O, V <sub>REF</sub>	3	P125	K16	N21	746
I/O (D4)	3	P126	J16	N22	749
I/O	3	-	J14	M19	752
I/O	3	P127	K15	M20	755
I/O	3	-	-	M18	758
V <sub>CCINT</sub>	-	P128	V <sub>CCINT</sub> *	V <sub>CCINT</sub> *	-
I/O, TRDY <sup>(1)</sup>	3	P129	J15	M22	764
V <sub>CCO</sub>	3	P130	V <sub>CCO</sub> Bank 3*	V <sub>CCO</sub> Bank 3*	-
V <sub>CCO</sub>	2	P130	V <sub>CCO</sub> Bank 2*	V <sub>CCO</sub> Bank 2*	-
GND	-	P131	GND*	GND*	-